

FAIRCHILD
SEMICONDUCTOR™

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74FR900 9-Bit, 3-Port Latchable Datapath Multiplexer

General Description

The 74FR900 is a data bus multiplexer routing any of three 9-bit ports to any other one of the three ports. Readback of data latched from any port onto itself is also possible. The 74FR900 maintains separate control of all latch-enable, output enable and select inputs for maximum flexibility. PINV allows inversion of the data from the C₈ to A₈ or B₈ path. This is useful for control of the parity bit in systems diagnostics.

Fairchild's 74FR25900 includes 25Ω resistors in series with port A and B outputs. Resistors minimize undershoot and ringing which may damage or corrupt sensitive device inputs driven by these ports.

Features

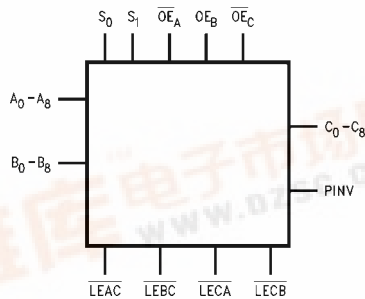
- 9-bit data ports for systems carrying parity bits
- Readback capability for system self checks.
- Independent control lines for maximum flexibility
- Guaranteed multiple output switching and 250 pF load delays
- Outputs optimized for dynamic bus drive capability
- PINV parity control facilitates system diagnostics
- FR25900 resistor option for driving MOS inputs such as DRAM arrays

Ordering Code:

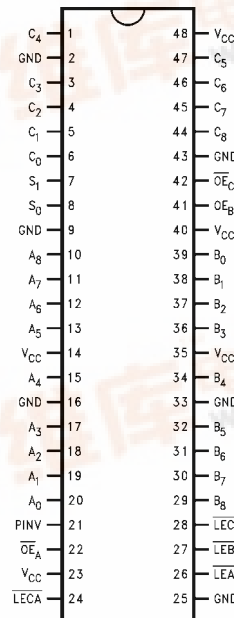
Order Number	Package Number	Package Description
74FR900SSC	MS48A	48-Lead Small Shrink Outline Package (SSOP), JEDEC MO-118, 0.300 Wide

Devices also available in Tape and Reel. Specify by appending the suffix letter "X" to the ordering code.

Logic Symbol



Connection Diagram



Pin Description

Pin Names	Description
LE _{xx}	Latch Enable Inputs
OE _x	Output Enable Inputs
PINV	Parity Invert Input
S ₀ , S ₁	Select Inputs
A ₀ -A ₈	Port A Inputs or 3-STATE Outputs
B ₀ -B ₈	Port B Inputs or 3-STATE Outputs
C ₀ -C ₈	Port C Inputs or 3-STATE Outputs

74FR900 9-Bit, 3-Port Latchable Datapath Multiplexer



Functional Description

The 74FR900 allows 9-bit data to be transferred from any of three 9-bit I/O ports to either of the two remaining I/O ports. The device employs latches in all paths for either transparent or synchronous operation. Readback capability from any port to itself is also possible.

Data transfer within the 74FR900 is controlled through use of the select (S_0 and S_1) and output-enable (\overline{OE}_A , OE_B and \overline{OE}_C) inputs as described in Table 1. Additional control is available by use of the latch-enable inputs (\overline{LEAC} , \overline{LECA} , \overline{LEBC} , \overline{LECB}) allowing either synchronous or transparent transfers (see Table 2). Table 1 indicates several readback conditions. By latching data on a given port and initiating the readback control configuration, previous data may be read for system verification or diagnostics. This mode may be useful in implementing system diagnostics.

Data at the port to be readback must be latched prior to enabling the outputs on that port. If this is not done, a closed data loop will result causing possible data integrity problems. Note that the A and B ports allow readback without affecting any other port. Port C, however, requires interruption of either port A or B to complete its readback path.

PINV controls inversion of the C_8 bit. A low on PINV allows C_8 data to pass unaltered. A high causes inversion of the data. See Table 3. This feature allows forcing of parity errors for use in system diagnostics. This is particularly helpful in 486 processor designs as the 486 does not provide odd/even parity selection internally.

TABLE 1. Datapath Control

Inputs					Function
S_0	S_1	\overline{OE}_A	OE_B	\overline{OE}_C	
L	X	H	L	L	Port A to Port C
L	L	H	H	H	Port A to Port B
L	O	H	H	L	Port A to B+C
H	L	L	L	H	Port B to Port A
H	X	H	L	L	Port B to Port C
H	O	L	L	L	Port B to A+C
X	H	L	L	H	Port C to Port A
X	H	H	H	H	Port C to Port B
X	H	L	H	H	Port C to A+B
X	X	H	L	H	Outputs Disabled
L	L	L	X	X	(Readback to A) (Note 1)
L	H	L	X	L	(Readback to A or C) (Note 1)
H	L	X	H	X	(Readback to B) (Note 1)
H	H	X	H	L	(Readback to B or C) (Note 1)

Note 1: Readback operation in latched mode only. Transparent operation could result in unpredictable results.

TABLE 2. Latch-Enable Control

\overline{LExx}	Input	Output
L	L	L
L	H	H
H	X	Q_0

L = LOW Voltage

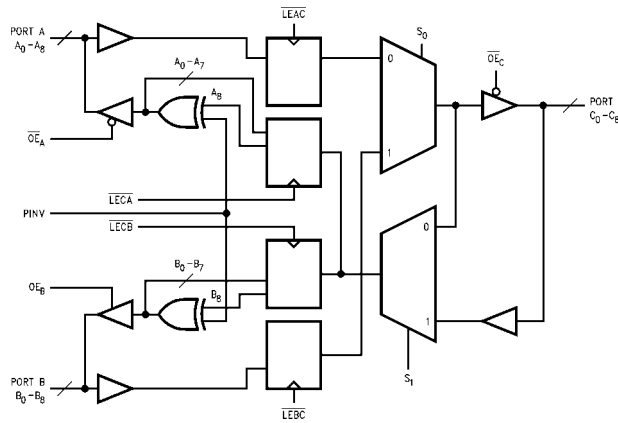
H = HIGH Voltage Level

TABLE 3. PINV Control

PINV	C_8	A_8 or B_8
L	L	L
L	H	H
H	L	H
H	H	L

Q_0 = Output state prior to \overline{LExx} LOW-to-HIGH transition

Logic Diagram



Absolute Maximum Ratings(Note 2)

Storage Temperature	-65°C to +150°C
Ambient Temperature under Bias	-55°C to +125°C
Junction Temperature under Bias	-55°C to +150°C
V _{CC} Pin Potential to Ground Pin	-0.5V to +7.0V
Input Voltage (Note 3)	-0.5V to +7.0V
Input Current (Note 3)	-30 mA to +5.0 mA
Voltage Applied to Output	
in HIGH State (with V _{CC} = 0V)	
Standard Output	-0.5V to V _{CC}
3-STATE Output	-0.5V to +5.5V
Current Applied to Output	
in LOW State (Max)	twice the rated I _{OL} (mA)
ESD Last Passing Voltage (Min)	4000V

Recommended Operating Conditions

Free Air Ambient Temperature	0°C to +70°C
Supply Voltage	+4.5V to +5.5V

Note 2: Absolute maximum ratings are values beyond which the device may be damaged or have its useful life impaired. Functional operation under these conditions is not implied.

Note 3: Either voltage limit or current limit is sufficient to protect inputs.

DC Electrical Characteristics

Symbol	Parameter	Min	Typ	Max	Units	V _{CC}	Conditions
V _{IH}	Input HIGH Voltage	2.0			V		Recognized HIGH Signal
V _{IL}	Input LOW Voltage			0.8	V		Recognized LOW Signal
V _{CD}	Input Clamp Diode Voltage			-1.2	V	Min	I _{IN} = -18 mA
V _{OH}	Output HIGH Voltage	2.4			V	Min	I _{OH} = -3 mA (A _n , B _n , C _n)
		2.0			V	Min	I _{OH} = -15 mA (A _n , B _n , C _n)
V _{OL}	Output LOW Voltage			0.50	V	Min	I _{OL} = 24 mA (A _n , B _n , C _n)
I _{IH}	Input HIGH Current			5	μA	Max	V _{IN} = 2.7V (Control Inputs)
I _{BVI}	Input HIGH Current Breakdown Test			7	μA	Max	V _{IN} = 7.0V (Control Inputs)
I _{BVIT}	Input HIGH Current Breakdown Test (I/O)			100	μA	Max	V _{IN} = 5.5V (A _n , B _n , C _n)
I _{IL}	Input LOW Current			-150	μA	Max	V _{IN} = 0.5V (Control Inputs)
V _{ID}	Input Leakage Test	4.75			V	0.0	I _{ID} = 1.9 μA, All Other Pins Grounded
I _{OD}	Output Circuit Leakage Test			3.75	V	0.0	V _{IOD} = 150 mV, All Other Pins Grounded
I _{IH} + I _{OZH}	Output Leakage Current			25	μA	Max	V _{OUT} = 2.7V (A _n , B _n , C _n)
I _{IIL} + I _{OZL}	Output Leakage Current			-150	μA	Max	V _{OUT} = 0.5V (A _n , B _n , C _n)
I _{OS}	Output Short Circuit Current	-100		-225	mA	Max	V _{OUT} = 0.0V (A _n , B _n , C _n)
I _{CEX}	Output HIGH Leakage Current			50	μA	Max	V _{OUT} = V _{CC} (A _n , B _n , C _n)
I _{ZZ}	Bus Drainage Test			100	μA	0.0	V _{OUT} = 5.25V (A _n , B _n , C _n)
I _{CCH}	Power Supply Current		115	150	mA	Max	All Outputs HIGH (Note 4)
I _{CCL}	Power Supply Current		170	200	mA	Max	All Outputs LOW (Note 4)
I _{CCZ}	Power Supply Current		147	175	mA	Max	Outputs in 3-STATE

Note 4: 2 ports active only

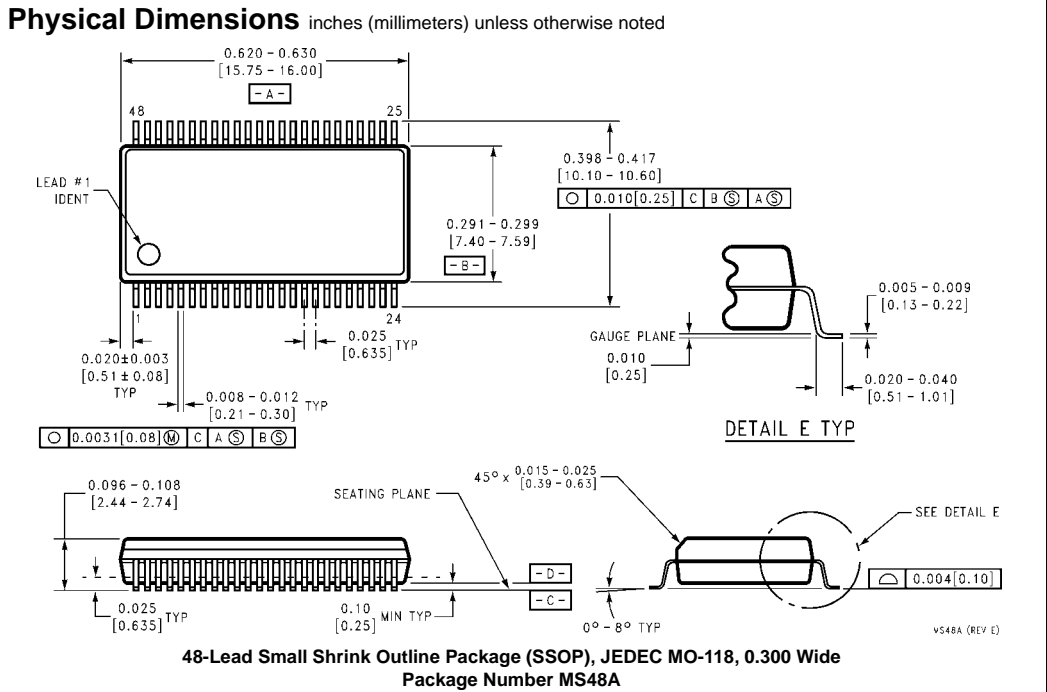
AC Electrical Characteristics							
Symbol	Parameter	$T_A = +25^\circ\text{C}$ $V_{CC} = +5.0\text{V}$ $C_L = 50\text{ pF}$			$T_A = 0^\circ\text{C to } +70^\circ\text{C}$ $V_{CC} = +5.0\text{V}$ $C_L = 50\text{ pF}$		Units
		Min	Typ	Max	Min	Max	
t_{PLH} t_{PHL}	Propagation Delay A_n or B_n to C_n C_n to A_n or B_n	2.0	4.2	7.0	2.0	7.0	ns
t_{PLH} t_{PHL}	Propagation Delay C_8 to A_8 or B_8 (PINV HIGH)	2.5	4.8	7.5	2.5	7.5	ns
t_{PLH} t_{PHL}	Propagation Delay A_n to B_n , B_n to A_n	4.5	6.4	10.0	4.5	10.0	ns
t_{PLH} t_{PHL}	Propagation Delay \overline{LEAC} to C_n , \overline{LEBC} to C_n	4.5	6.8	10.0	4.5	10.0	ns
t_{PLH} t_{PHL}	Propagation Delay \overline{LECA} to A_n , \overline{LECB} to B_n	3.0	6.0	9.5	3.0	9.5	ns
t_{PLH} t_{PHL}	Propagation Delay S_0 to C_n	3.0	6.0	10.0	3.0	10.0	ns
t_{PLH} t_{PHL}	Propagation Delay S_1 to A_n or B_n	3.5	6.5	11.0	3.5	11.0	ns
t_{PLH} t_{PHL}	Propagation Delay PINV to A_8 or B_8	2.0	5.0	9.0	2.0	9.0	ns
t_{PZH} t_{PZL}	Output Enable Time A_n , C_n	2.0	4.0	6.5	2.0	6.5	ns
t_{PHZ} t_{PLZ}	Output Disable Time A_n , C_n	1.5	4.0	6.0	1.5	6.0	ns
t_{PZH} t_{PZL}	Output Enable Time B_n	2.0	5.0	7.0	2.0	7.0	ns
t_{PHZ} t_{PLZ}	Output Disable Time B_n	2.0	5.0	7.0	2.0	7.0	ns
AC Operating Requirements							
Symbol	Parameter	$T_A = +25^\circ\text{C}$ $V_{CC} = +5.0\text{V}$ $C_L = 50\text{ pF}$			$T_A = 0^\circ\text{C to } +70^\circ\text{C}$ $V_{CC} = +5.0\text{V}$ $C_L = 50\text{ pF}$		Units
		Min	Typ	Max	Min	Max	
$t_{S(H)}$ $t_{S(L)}$	Setup Time, HIGH or LOW A_n to \overline{LEAC} , B_n to \overline{LEBC}	4.0	2.0		4.0		ns
$t_{H(H)}$ $t_{H(L)}$	Hold Time, HIGH or LOW A_n to \overline{LEAC} , B_n to \overline{LEBC}	1.0	-2.0		1.0		ns
$t_{S(H)}$ $t_{S(L)}$	Setup Time, HIGH or LOW C_n to \overline{LECA} or \overline{LECB}	3.0	1.0		3.0		ns
$t_{H(H)}$ $t_{H(L)}$	Hold Time, HIGH or LOW C_n to \overline{LECA} or \overline{LECB}	1.0	-1.0		1.0		ns
$t_W(H)$	\overline{LE} Pulse Width LOW	8.0	4.0		8.0		ns
Extended AC Electrical Characteristics							
Symbol	Parameter	$T_A = 0^\circ\text{C to } +70^\circ\text{C}$ $V_{CC} = +5.0\text{V}$ $C_L = 50\text{ pF}$ Nine Outputs Switching (Note 5)		$T_A = 0^\circ\text{C to } +70^\circ\text{C}$ $V_{CC} = +5.0\text{V}$ $C_L = 250\text{ pF}$ (Note 6)		Units	
		Min	Max	Min	Max		
t_{PLH}	Propagation Delay						

Extended AC Electrical Characteristics (Continued)

Symbol	Parameter	$T_A = 0^\circ\text{C to } +70^\circ\text{C}$ $V_{CC} = +5.0\text{V}$ $C_L = 50\text{ pF}$ Nine Outputs Switching (Note 5)		$T_A = 0^\circ\text{C to } +70^\circ\text{C}$ $V_{CC} = +5.0\text{V}$ $C_L = 250\text{ pF}$ (Note 6)		Units
		Min	Max	Min	Max	
		t_{PHL}	A_n or B_n to C_n C_n to A_n or B_n	2.0	9.0	
t_{PLH}	Propagation Delay					
t_{PHL}	C_8 to A_8 or B_8 (PINV HIGH)			3.5	11.0	ns
t_{PLH}	Propagation Delay					
t_{PHL}	A_n to B_n , B_n to A_n	4.5	12.0	5.5	13.5	ns
t_{PLH}	Propagation Delay					
t_{PHL}	\overline{LEAC} to C_n , \overline{LEBC} to C_n	4.5	12.0	5.5	13.5	ns
t_{PLH}	Propagation Delay					
t_{PHL}	\overline{LECA} to A_n , \overline{LECB} to B_n	3.0	11.5	4.0	13.5	ns
t_{PLH}	Propagation Delay					
t_{PHL}	S_0 to C_n	3.0	11.0	3.0	14.0	ns
t_{PLH}	Propagation Delay					
t_{PHL}	S_1 to A_n or B_n	3.5	12.0	4.5	15.0	ns
t_{PLH}	Propagation Delay					
t_{PHL}	PINV to A_8 or B_8			2.5	12.0	ns
t_{PZH}	Output Enable Time					
t_{PZL}	A_n , C_n	2.0	8.0			ns
t_{PHZ}	Output Disable Time					
t_{PLZ}	A_n , C_n	1.5	6.0			ns
t_{PZH}	Output Enable Time					
t_{PZL}	B_n	2.0	8.0			ns
t_{PHZ}	Output Disable Time					
t_{PLZ}	B_n	2.0	7.0			ns

Note 5: This specification is guaranteed but not tested. The limits apply to propagation delays for all paths described switching in phase, i.e., all LOW-to-HIGH, HIGH-to-LOW, 3-STATE-to-HIGH, etc.

Note 6: This specification is guaranteed but not tested. The limits represent propagation delays with 250 pF load capacitors in place of the 50 pF load capacitors standard AC load. This specification pertains to single output switching only.



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